

In the Claims:

Please amend claims 1, 13, and 25 as follows:

1. (amended) An electrical test probe comprising:

5 a probe body;

a probe tip mechanically coupled to said probe body, wherein said probe tip is  
capable of being non-permanently electrically coupled to an external test  
instrument; and

10 a control device mechanically coupled to said probe body, wherein said  
control device is capable of being non-permanently electrically coupled to  
said test instrument.

13. (amended) An electrical test probe comprising:

a probe body;

a probe tip mechanically coupled to said probe body;

15 a control device mechanically coupled to said probe body; and

a communication port mechanically coupled to said probe body, and

electrically coupled to said control device and said probe tip, wherein said  
communication port is capable of being non-permanently electrically  
coupled to an external electrical test instrument.

20 25. (amended) An electrical test probe comprising:

a probe body;

a probe tip mechanically coupled to said probe body;

a cable electrically coupled to said probe tip, mechanically coupled to said probe body, and non-permanently electrically and mechanically coupled to an external electrical test instrument; and

a control device mechanically coupled to said probe body and electrically coupled to said cable, wherein said control device, when activated, activates a function of said test instrument.